HARRIS SEMICONDUCTOR

HS-6504RH

Radiation Hardened 4096 x 1 CMOS RAM

December 1992

Features

- Total Dose 1 x 10^5 RAD (Si)
- Data Upset > 10^8 RAD (Si)/s
- Latch-Up Free To > 1 x 10^{12} RAD (Si)/s
- Low Power Standby 1100µW Max
- Low Power Operation 38.5mW/MHz Max
- Fast Access Time 150ns Typ
- Extremely Low Speed Power Product
- Single Event Upset Immune Option
- TTL Compatible Output
- Three-State Outputs
- Standard JEDEC Pinout
- 18 Pin Package for High Density
- On-Chip Address Register
- Military Temperature Range -55°C to +125°C

Description

The HS-6504RH is a synchronous 4096 x 1 static CMOS RAM fabricated using the radiation hardened guard band, self-aligned silicon gate technology. The device utilizes synchronous circuitry to achieve high performance and low power operation.

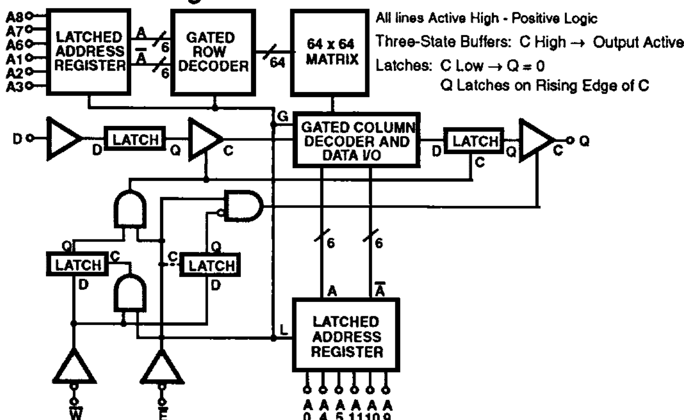
Latch-up free operation is achieved by the use of epitaxial starting material to eliminate the parasitic SCR effect seen in conventional bulk CMOS devices. On-chip latches are provided for addresses, data input and data output allowing efficient interfacing with microprocessor systems. The data output can be forced to a high impedance state for use in expanded memory arrays.

The HS-6504RH is a fully static RAM and may be maintained in any state for an indefinite period of time. A single event upset immune version of the HS6504RRH is also offered. See page 11-5.

JAN

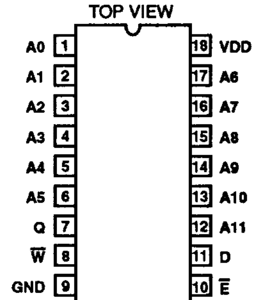
On January 28, 1987, Harris received JAN line certification as a Rad-Hard Class S fabrication facility for the HS-6504RH. Specifications can be found in JAN 38510/245 under device type 03.

Functional Diagram

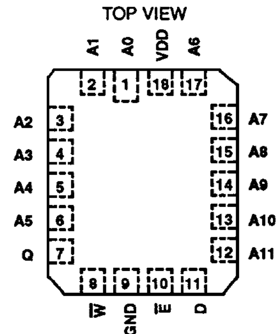


Pinouts

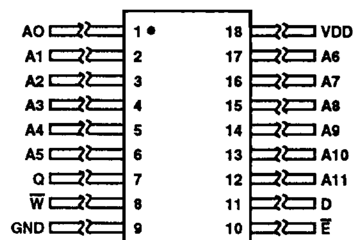
HS1-6504RH 18 PIN CERAMIC DIP
CASE OUTLINE D-6, CONFIGURATION 3
TOP VIEW



HS4-6504RH 18 PIN LCC
INTERNAL PACKAGE CODE "HPQ"
TOP VIEW



HS9-6504RH 18 LEAD FLATPACK
INTERNAL PACKAGE CODE "HRF"
TOP VIEW



PIN	DESCRIPTION
A	Address Input
$\overline{E}$	Chip Enable
$\overline{W}$	Write Enable
D	Data Input
Q	Data Output

CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper I.C. Handling Procedures.

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File Number 3028

Absolute Maximum Ratings

Supply Voltage -(VDD-GND) . . . . -0.3 to +7.0V
Input or Output Voltage Applied . . . . .GND-0.3V to VDD +0.3V
Storage Temperature Range . . . . -65°C to +150°C
Junction Temperature. . . . . +175°C
Lead Temperature (Soldering 10s). . . . . +300°C
Typical Derating Factor. . . . . .3.0mA/MHz Increase in IDDOP
ESD Classification . . . . Class 1

Reliability Information

Thermal Resistance	θ_{ja}	θ_{jc}
18 Pin Ceramic DIP Package	73°C/W	10°C/W
18 Pin LCC Package	60°C/W	9°C/W
18 Lead Flatpack Package	62°C/W	10°C/W

Maximum Package Power Dissipation at +125°C
18 Pin Ceramic DIP Package 0.68W
18 Pin LCC Package 0.83W
18 Lead Flatpack Package 0.80W
Gate Count . . . . 6667 Gates

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Operating Conditions

Operating Supply Voltage Range. . . . . +4.5V to +5.5V
Operating Temperature Range. . . . . -55°C to +125°C
Input Rise and Fall Time . . . . 40ns Max

TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS

PARAMETER	SYMBOL	CONDITIONS	LIMITS		UNITS
			MIN	MAX	
Standby Supply Current	IDDSB	IO = 0, VI = GND or VDD	-	200	µA
Operating Supply Current (Note 1)	IDDOP	f = 1MHz, IO = VI = VDD or GND	-	7	mA
Data Retention Supply Current	IDDDR		-	100	µA
Data Retention Supply Voltage	VDDDR		-	3.0	V
Input Leakage Current	II	GND ≤ VI ≤ VDD	-1.0	+1.0	µA
Output Leakage Current	IOZ	GND ≤ VO ≤ VDD	-10	+10	µA
Input Low Voltage	VIL		0.0	0.8	V
Input High Voltage All Except E and R/W	VIH		VDD -2.0	VDD	V
Input High Voltage E and R/W	VIH		VDD -1.5	VDD +0.3	
Output Low Voltage	VOL	IOL = 2.0mA	-	0.4	V
Output High Voltage	VOH	IOH = -1.0mA	2.4	-	V

NOTE:

1. Operating Supply Current (IDDOP) is proportional to Operating Frequency.

TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS

PARAMETER	SYMBOL	CONDITIONS	LIMITS		UNITS
			MIN	MAX	
Chip Enable Access Time	TELQV	Note 1	-	200	ns
Address Access Time	TAVQV	Note 1	-	210	ns
Chip EnableTime	TELEH	Note 1	200	-	ns
Chip Disable Time	TEHEL	Note 1	50	-	ns
Address Setup Time	TAVEL	Note 1	10	-	ns
Address Hold Time	TELAX	Note 1	40	-	ns
Write Enable Pulse Width	TWLWH	Note 1	50	-	ns
Write Enable Setup Time	TWLEH	Note 1	200	-	ns
Early Write Pulse Setup Time	TWLEL	Note 1	0	-	ns
Write Enable Hold Time	TELWH	Note 1	50	-	ns
Data Setup Time	TDVWL	Note 1	10	-	ns

TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)

PARAMETER	SYMBOL	CONDITIONS	LIMITS		UNITS
			MIN	MAX	
Early Write Data Setup Time	TDVEL	Note 1	0	-	ns
Data Hold Time	TWLDX	Note 1	50	-	ns
Early Write Data Hold	TELDX	Note 1	50	-	ns
Data Valid to Write Time	TQVWL	Note 1	0	-	ns

NOTE:

1. Inputs TRISE = TFALL ≤ 20nsec: Outputs : 1TTL load and 50pF. All timing measurements at 1/2 VDD.

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (Guaranteed but not tested)

PARAMETER	SYMBOL	CONDITIONS	LIMITS		UNITS
			MIN	MAX	
Input Capacitance	CI	VI = VDD or GND	-	8.0	pF
Output Capacitance	CO	VO = VDD or GND, f = 1MHz	-	10.0	pF
Chip Enable/Output Enable Time	TELQX	Note 1	5	-	ns
Chip Enable/Output Disable Time	TEHQZ	Note 1	-	50	ns
Read Mode Write Enable Setup Time	TWHEL	Note 1	0	-	ns
Read or Write Cycle Time	TELEL	Note 1	250	-	ns

NOTE:

1. Inputs TRISE = TFALL ≤ 20nsec: Outputs : 1TTL load and 50pF. All timing measurements at 1/2 VDD.

TABLE 4. POST RAD ELECTRICAL PERFORMANCE CHARACTERISTICS

NOTE: The post irradiation test conditions and limits are the same as those listed in Tables 1 and 2.

TABLE 5. BURN-IN DELTA PARAMETERS (+25°C)

PARAMETER	SYMBOL	DELTA LIMITS
Output Low Voltage	VOL	± 0.08V
Output High Voltage	VOH	± 0.48V
Input Leakage Current	II	± 0.20µA

TABLE 6. APPLICABLE SUBGROUPS

CONFORMANCE GROUPS		METHOD	-Q SUBGROUPS	-8 SUBGROUPS
Initial Test		100%/5004	1, 7, 9	1, 7, 9
Interim Test 1 and 2		100%/5004	1, 7, 9	N/A
PDA 1 and 2		100%/5004	1, 7, Δ	1, 7
Final Test		100%/5004	2, 3, 8A, 8B, 10, 11	2, 3, 8A, 8B, 10, 11
Group A		Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group B (Optional)	B5	Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	N/A
	Others	Samples/5005	1, 7	N/A
Group C (Optional)		Samples/5005	N/A	1, 7
Group D (Optional)		Samples/5005	1, 7	1, 7
Group E, Subgroup 2		Samples/5005	1, 7, 9	1, 7, 9

Absolute Maximum Ratings

Supply Voltage -(VDD-GND) . . . . -0.3 to +7.0V
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Thermal Resistance	θ_{ja}	θ_{jc}
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CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

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Operating Supply Voltage Range . . . . +4.5V to +5.5V
Operating Temperature Range . . . . -20°C to +80°C
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Input Low Voltage	VIL		0.0	0.8	V
Input High Voltage All Except E and R/W	VIH		VDD -2.0	VDD	V
Input High Voltage E and R/W	VIH		VDD -1.5	VDD +0.3	
Output Low Voltage	VOL	IOL = 2.0mA	-	0.4	V
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Address Hold Time	TELAX	Note 1	40	-	ns
Write Enable Pulse Width	TWLWH	Note 1	50	-	ns
Write Enable Setup Time	TWLEH	Note 1	200	-	ns
Early Write Pulse Setup Time	TWLEL	Note 1	0	-	ns
Write Enable Hold Time	TELWH	Note 1	50	-	ns
Data Setup Time	TDVWL	Note 1	10	-	ns

TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)

PARAMETER	SYMBOL	CONDITIONS	LIMITS		UNITS
			MIN	MAX	
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Data Hold Time	TWLDX	Note 1	50	-	ns
Early Write Data Hold	TELDX	Note 1	50	-	ns
Data Valid to Write Time	TQVWL	Note 1	0	-	ns

NOTE:

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Output Capacitance	CO	VO = VDD or GND, f = 1MHz	-	10.0	pF
Chip Enable/Output Enable Time	TELQX	Note 1	5	-	ns
Chip Enable/Output Disable Time	TEHQZ	Note 1	-	50	ns
Read Mode Write Enable Setup Time	TWHEL	Note 1	0	-	ns
Read or Write Cycle Time	TELEL	Note 1	250	-	ns

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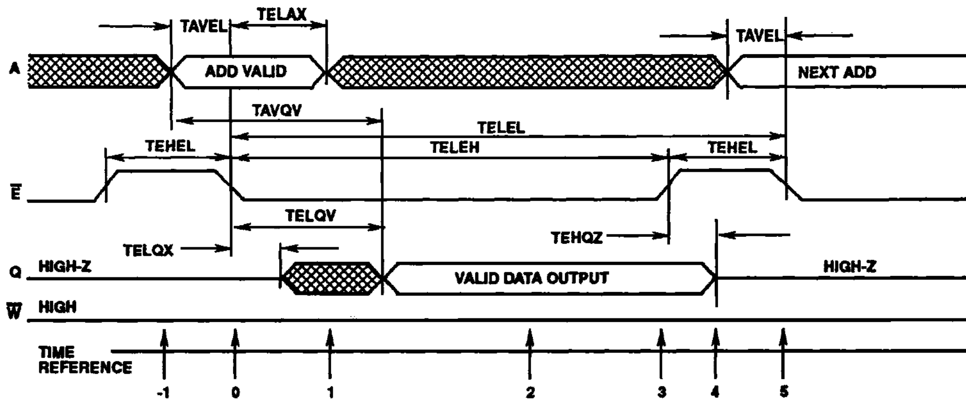
Initial Test		100%/5004	1, 7, 9	1, 7, 9
Interim Test 1 and 2		100%/5004	1, 7, 9	N/A
PDA 1 and 2		100%/5004	1, 7, Δ	1, 7
Final Test		100%/5004	2, 3, 8A, 8B, 10, 11	2, 3, 8A, 8B, 10, 11
Group A		Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group B (Optional)	B5	Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	N/A
	Others	Samples/5005	1, 7	N/A
Group C (Optional)		Samples/5005	N/A	1, 7
Group D (Optional)		Samples/5005	1, 7	1, 7
Group E, Subgroup 2		Samples/5005	1, 7, 9	1, 7, 9

Timing Waveforms

READ CYCLE



TRUTH TABLE

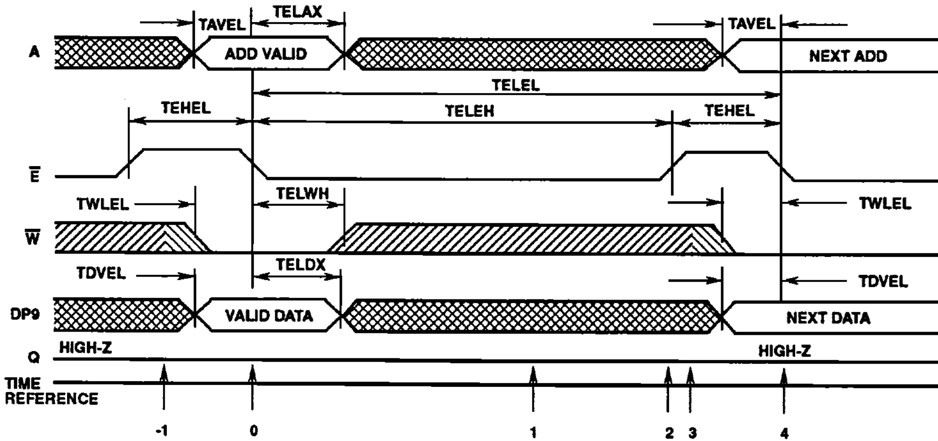
TIME REFERENCE	INPUTS			OUTPUT	FUNCTION
	$\overline{E}$	$\overline{W}$	A	Q	
-1	H	X	X	Z	Memory Disabled
0	↘	H	V	Z	Cycle Begins, Addresses are Latched
1	L	H	X	X	Output Enabled
2	L	H	X	V	Output Valid
3	↗	H	X	V	Read Accomplished
4	H	X	X	Z	Prepare for Next Cycle (Same as -1)
5	↘	H	V	Z	Cycle Ends, Next Cycle Begins (Same as 0)

The address information is latched in the on chip registers on the falling edge of $\overline{E}$ (T = 0). Minimum address set up and hold time requirements must be met. After the required hold time, the addresses may change state without affecting device operation. During time (T = 1) the output becomes enabled but the data is not valid until during time (T = 2). $\overline{W}$ must remain high for the read cycle. After the output data has been read, $\overline{E}$ may return high (T = 3). This will disable the output buffer and all input and ready the RAM for the next memory cycle (T = 4).

NOTE: In the above descriptions the numbers in parenthesis (T = n) refer to the respective timing diagrams. The numbers are located on the time reference line below each diagram. The timing diagrams shown are only examples and are not the only valid method of operation.

Timing Waveforms (Continued)

EARLY WRITE CYCLE



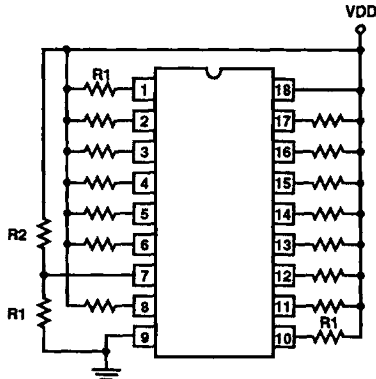
TRUTH TABLE

TIME REFERENCE	INPUTS				OUTPUT	FUNCTION
	$\overline{E}$	$\overline{W}$	A	D	Q	
-1	H	X	X	X	Z	Memory Disabled
0	↓	L	V	V	Z	Cycle Begins, Addresses are Latched
1	L	X	X	X	Z	Write in Progress Internally
2	↑	X	X	X	Z	Write Completed
3	H	X	X	X	Z	Prepare for Next Cycle (Same as - 1)
4	↓	L	V	V	Z	Cycle Ends, Next Cycle Begins (Same as 0)

The early write cycle is the only cycle where the output is guaranteed not to become active. On the falling edge of $\overline{E}$ (T = 0), the addresses, the write signal, and the data input are latched in on chip registers. The logic value of $\overline{W}$ at the time $\overline{E}$ falls determines the state of the output buffer for that cycle. Since $\overline{W}$ is low when $\overline{E}$ falls, the output buffer is latched into the high impedance state and will remain in that state until $\overline{E}$ returns high (T = 2). For this cycle, the data input is latched by $\overline{E}$ going low; therefore data set up and hold times should be referenced to $\overline{E}$. When $\overline{E}$ (T = 2) returns to the high state the output buffer and all inputs are disabled and all signals are unlatched. The device is now ready for the next cycle.

NOTE: In the above descriptions the numbers in parenthesis (T = n) refer to the respective timing diagrams. The numbers are located on the time reference line below each diagram. The timing diagrams shown are only examples and are not the only valid method of operation.

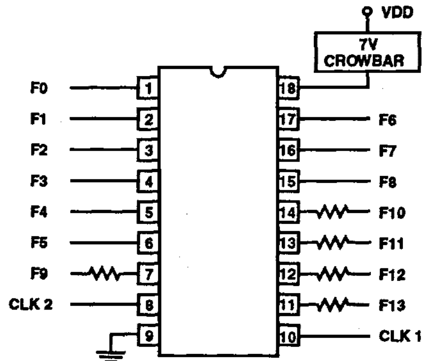
Burn-In Circuits

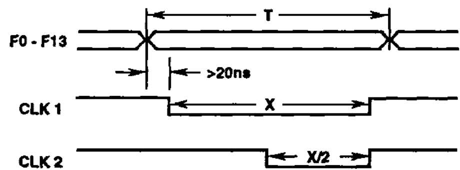


STATIC CONFIGURATION

NOTES:

VDD = 6.0V ± 0.5V
R1 = 1K
R2 = 1.5k
Minimum Ambient Temperature = +125°C



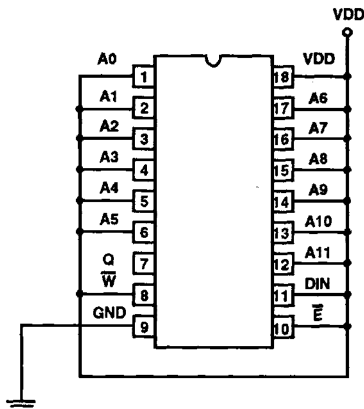


DYNAMIC CONFIGURATION

NOTES:

VDD = 6.0V ± 0.5V
All Resistors = 27KΩ
Minimum Ambient Temperature = +125°C
VDD must be applied before or at the same time as input signals
x > 700ns, T = 5µs
F0 = 100kHz
F1 = F0/2
F2 = F0/4
F3 = F0/8 . . . F13 = F0/8192

Irradiation Circuit



NOTES:

VDD = 5V
GND = 0V
All Inputs = 5V
All outputs float
MONITOR: IDD at 5V

Harris - Space Level (-Q) Product Flow (Note 1)

SEM - Traceable to Diffusion Method 2018
Wafer Lot Acceptance Method 5007
Internal Visual Inspection Method 2010, Condition A
Gamma Radiation Assurance Tests Method 1019
Nondestructive Bond Pull Method 2023
Customer Pre-Cap Visual Inspection (Note 2)
Temperature Cycling Method 1010, Condition C
Constant Acceleration Method 2001, Condition E Min, Y1
Particle Impact Noise Detection Method 2020, Condition A
Electrical Tests (Harris' Option)
Serialization
X-Ray Inspection Method 2012
Electrical Tests - Subgroup 1; Read and Record (T0)
Static Burn-In Method 1015, Condition B, 72 Hrs, +125°C Min.
Interim 1 Electrical Tests - Subgroup 1; Read and Record (T1)
Burn-In Delta Calculation (T0 -T1)
PDA Calculation 3% Subgroup 7
5% Subgroups 1, 7, Δ
Dynamic Burn-In Method 1015, Condition D, 240 Hrs, +125°C (Note 3)
Interim 2 Electrical Tests - Subgroup 1; Read and Record (T2)
Alternate Group A - Subgroups 1, 7, 9; Method 5005; Para 3.5.1.1
Burn-In Delta Calculation (T0 - T2)
PDA Calculation 3% Subgroup 7
5% Subgroups 1, 7, Δ
Electrical Tests - Subgroup 3; Read and Record
Alternate Group A - Subgroups 3, 8B, 11; Method 5005; Para 3.5.1.1
Marking
Electrical Tests - Subgroup 2; Read and Record
Alternate Group A - Subgroups 2, 8A, 10; Method 5005; Para 3.5.1.1
Gross Leak Tests Method 1014, 100%
Fine Leak Tests Method 1014, 100%
Customer Source Inspection (Note 2)
Group B Inspection Method 5005 (Note 2)
End-Point Electrical Parameters: B-5 - Subgroups 1, 2, 3, 7, 8A, 8B, 9, 10, 11; B-6 - Subgroups 1, 7, 9
Group D Inspection Method 5005 (Notes 2, 4)
End-Point Electrical Parameters: Subgroups 1, 7, 9
External Visual Inspection Method 2009
Data Package Generation (Note 5)

NOTES:

1. The notes of Method 5004, Table 1 shall apply; Unless Otherwise Specified.
2. These steps are optional, and should be listed on the individual purchase order(s), when required.
3. Harris reserves the right of performing burn-in time temperature regression as defined by Table 1 of Method 1015.
4. For Group D, Subgroup 3 inspection of package configurations which utilizes a gold plated lid in its construction; the inspection criteria for illegible markings criteria of Method 1010, paragraph 3.3 and of Method 1004, paragraph 3.8.a shall not apply.
5. Data package contains:
   Assembly Attributes (post seal)
   Test Attributes (includes Group A)
   Shippable Serial Number List
   Radiation Testing Certificate of Conformance
   Wafer Lot Acceptance Report (Including SEM Report)
   X-Ray Report and Film
   Test Variables Data

Harris -8 Product Flow

Internal Visual Inspection
Gamma Radiation Assurance Tests Method 1019
Customer Pre-Cap Visual Inspection (Note 1)
Temperature Cycling Method 1010, Condition C
Fine and Gross Leak Tests Method 1014
Constant Acceleration Method 2001 Y1 30KG
Initial Electrical Tests
Dynamic Burn-In Method 1015, Condition D, 160 Hrs, +125°C
+25°C Electrical Tests - Subgroups 1, 7, 9
PDA Calculation 5% Subgroups 1, 7
Electrical Tests +125°C, -55°C
Group A Inspection Method 5005. 5% PDA (Note 3)
Brand
Customer Source Inspection (Note 1)
Group C Inspection Method 5005 (Notes 1, 2)
Group D Inspection Method 5005 (Notes 1, 2)
External Visual Inspection Method 2009
Data Package Generation (Note 4)

NOTES:

1. These steps are optional, and must be negotiated as part of order.
2. Group B and D data package contains Attributes Data plus Variables Data.
3. Harris reserves the right to perform Alternate Group A. The 5% PDA is still applicable.
4. '-8' Data package contains:
   Assembly Attributes (post seal)
   Test Attributes (includes Group A)
   Radiation Testing Certificate of Conformance
   Certificate of Conformance (as found on shipper)

Metallization Topology

DIE DIMENSIONS:
Die Size: 154 x 236 mils
Die Thickness: 14 ±1 mils

METALLIZATION:
Type: Al, 14kÅ ± 2kÅ
Back: Gold

GLASSIVATION:
Type: SiO_2
Thickness: 8kÅ ± 1kÅ

DIE ATTACH:
Material: Gold
Temperature: Sidebrazed Ceramic DIP - 460°C±10°C (Max)
Braze Seal Flatpack - 460°C ± 10°C (Max)

WORST CASE CURRENT DENSITY: 6.44×10^4 A/cm^2

SUBSTRATE POTENTIAL: VDD

Metallization Mask Layout

HS-6504RH